

FDP7045L/FDB7045L

N-Channel Logic Level PowerTrench^o MOSFET

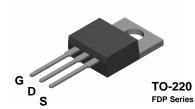
General Description

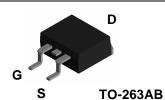
This N-Channel Logic Level MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

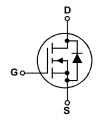
These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable $R_{\text{DS(ON)}}$ specifications resulting in DC/DC power supply designs with higher overall efficiency.

Features

- 100 A, 30 V $R_{DS(ON)} = 4.5 \text{ m}\Omega$ @ $V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 6.0 \text{ m}\Omega$ @ $V_{GS} = 4.5 \text{ V}$
- Critical DC electrical parameters specified at elevated temperature
- High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$
- 175°C maximum junction temperature rating







Absolute Maximum Ratings T_A=25°C unless otherwise noted

| Symbol | Parameter | | Ratings | Units |
|-----------------------------------|--------------------------------------------------|----------|-------------|-------|
| V _{DSS} | Drain-Source Voltage | | 30 | V |
| V _{GSS} | Gate-Source Voltage | | ± 20 | V |
| I _D | Drain Current - Continuous | (Note 1) | 100 | А |
| | | | 75 | |
| | - Pulsed | (Note 1) | 300 | |
| P_D | Total Power Dissipation @ T _C = 25°C | | 107 | W |
| | Derate above 25°C | | 0.7 | W/°C |
| T _J , T _{STG} | Operating and Storage Junction Temperature Range | | -55 to +175 | °C |

FDB Series

Thermal Characteristics

| $R_{\theta JC}$ | Thermal Resistance, Junction-to-Case | 1.4 | °C/W |
|-----------------|-----------------------------------------|------|------|
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient | 62.5 | °C/W |

Package Marking and Ordering Information

| Device Marking | Device | Reel Size | Tape width | Quantity |
|-------------------|----------|-----------|------------|-----------|
| FDB7045L | FDB7045L | 13" | 24mm | 800 units |
| FDP7045L FDP7045L | | Tube | n/a | 45 |

| Symbol | Parameter | Test Conditions | Min | Тур | Max | Units |
|---------------------------------------------|---------------------------------------------------|-------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|-----|-------------------|-------------------|-------|
| Drain-Sc | ource Avalanche Ratings (Note | 1) | | • | | |
| W _{DSS} | Single Pulse Drain-Source Avalanche Energy | $V_{DD} = 15 \text{ V}, \qquad I_{D} = 75 \text{ A}$ | | | 330 | mJ |
| I _{AR} | Maximum Drain-Source Avalanche Current | | | | 75 | Α |
| Off Char | acteristics | | | | | |
| BV _{DSS} | Drain-Source Breakdown Voltage | $V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \mu\text{A}$ | 30 | | | V |
| <u>ΔBV_{DSS}</u> ΔT _J | Breakdown Voltage Temperature Coefficient | I_D = 250 μ A, Referenced to 25°C | | 25 | | mV/°C |
| I _{DSS} | Zero Gate Voltage Drain Current | $V_{DS} = 24 \text{ V}, \qquad V_{GS} = 0 \text{ V}$ | | | 1 | μΑ |
| I _{GSS} | Gate-Body Leakage | $V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$ | | | ± 100 | nA |
| On Char | acteristics (Note 2) | | • | | | |
| V _{GS(th)} | Gate Threshold Voltage | $V_{DS} = V_{GS}, I_{D} = 250 \mu A$ | 1 | 1.8 | 3 | V |
| $\Delta V_{GS(th)} \over \Delta T_J$ | Gate Threshold Voltage Temperature Coefficient | I_D = 250 μ A, Referenced to 25°C | | -6 | | mV/°C |
| R _{DS(on)} | Static Drain–Source On– Resistance | $V_{GS} = 10 \text{ V}, \qquad I_D = 50 \text{ A}$ $V_{GS} = 4.5 \text{ V}, \qquad I_D = 40 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 50 \text{ A}, T_J = 125^{\circ}\text{C}$ | | 3.5 4.0 5.5 | 4.5 6.0 7.0 | mΩ |
| I _{D(on)} | On-State Drain Current | $V_{GS} = 10 \text{ V}, \qquad V_{DS} = 10 \text{ V}$ | 50 | | | Α |
| g FS | Forward Transconductance | $V_{DS} = 5V$, $I_{D} = 50 \text{ A}$ | İ | 165 | | S |
| Dvnamio | Characteristics | | | | | |
| C _{iss} | Input Capacitance | $V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$ | | 2440 | | pF |
| Coss | Output Capacitance | f = 1.0 MHz | | 580 | | pF |
| C _{rss} | Reverse Transfer Capacitance | 7 | | 250 | | pF |
| R _G | Gate Resistance | V _{GS} = 15 mV, f = 1.0 MHz | | 1.4 | | Ω |
| Switchin | g Characteristics (Note 2) | | | | | |
| t _{d(on)} | Turn-On Delay Time | $\begin{aligned} V_{DD} &= 15 \text{V}, & I_D &= 1 \text{ A}, \\ V_{GS} &= 10 \text{ V}, & R_{GEN} &= 6 \Omega \end{aligned}$ | | 16 | 29 | ns |
| t _r | Turn-On Rise Time | | | 13 | 24 | ns |
| t _{d(off)} | Turn-Off Delay Time | 1 | | 74 | 119 | ns |
| t _f | Turn-Off Fall Time | 1 | | 41 | 66 | ns |
| Q _g | Total Gate Charge | $V_{DS} = 15 \text{ V}, \qquad I_{D} = 50 \text{ A},$ | | 41 | 58 | nC |
| Q _{gs} | Gate-Source Charge | $V_{GS} = 5 V$ | | 12 | | nC |
| Q_{gd} | Gate-Drain Charge | | | 14 | | nC |
| Drain-Se | ource Diode Characteristics | and Maximum Ratings | | | | |
| Is | Maximum Continuous Drain-Source | | | | 75 | Α |
| V _{SD} | Drain-Source Diode Forward Voltage | $V_{GS} = 0 \text{ V}, I_{S} = 50 \text{ A}$ (Note 1) | | 0.91 | 1.2 | V |
| t _{rr} | Diode Reverse Recovery Time | I _F = 50 A, | | 48 | | nS |
| Q _{rr} | Diode Reverse Recovery Charge | $d_{iF}/d_{t} = 100 \text{ A}/\mu\text{s}$ | | 42 | | nC |

Notes:

- 1. Calculated continuous current based on maximum allowable junction temperature. Actual maximum continuous current limited by package constraints to 75A.
- 2. Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%

Typical Characteristics

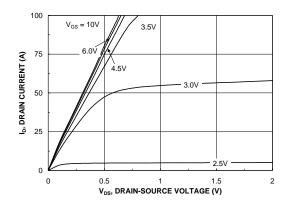


Figure 1. On-Region Characteristics.

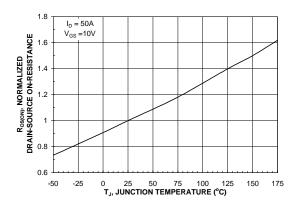


Figure 3. On-Resistance Variation with Temperature.

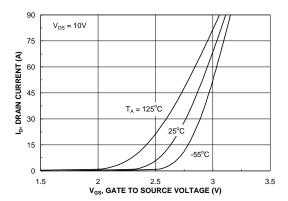


Figure 5. Transfer Characteristics.

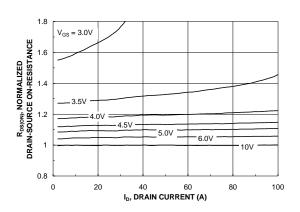


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

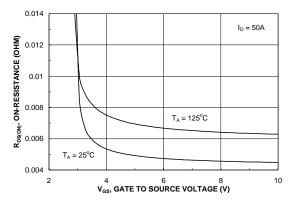


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

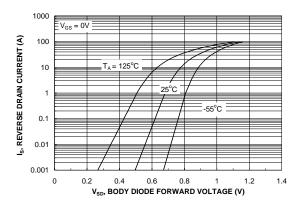
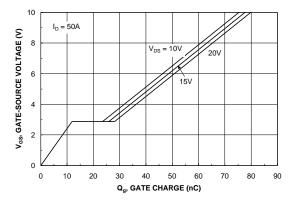


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



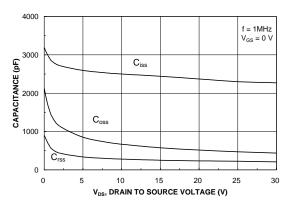
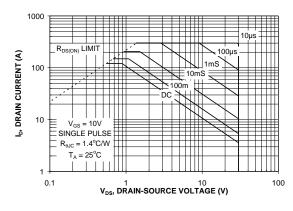


Figure 7. Gate Charge Characteristics.





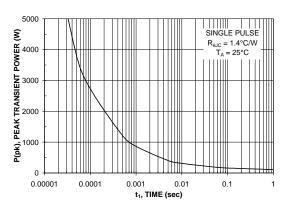


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

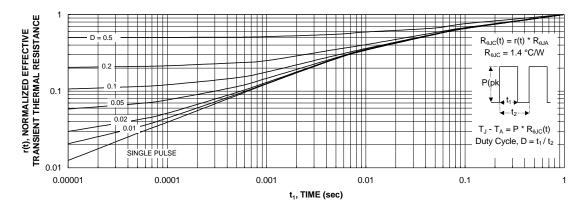


Figure 11. Transient Thermal Response Curve.

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